

Laboratory SMIT EMI/EMC Laboratory, E-5/2, Chakan Industrial Area, Phase III, M.I.D.C., Nanekarwadi, Tal.- Khed, Pune, Maharashtra
Accreditation Standard ISO/IEC 17025: 2005
Certificate Number TC-8007 **Page 1 of 4**
Validity 23.10.2018 to 22.10.2020 **Last Amended on --**

Sl.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
-----	----------------------------	-------------------------	---	--

ELECTRONIC TESTING

I.	EMC TESTING FACILITY			
1.	Electronic Sub Assembly for Automobile	Radiated Emission (RE)	Antenna method: CISPR 25 (Edition 4) CISPR 25 (Edition 3) AIS-004 (Part 3)	150 kHz to 2500 MHz Class 5
		Conducted Emission- Power supply and Interconnect lines (CE)	Voltage Method: CISPR 25 (Edition 4) CISPR 25 (Edition 3)	150 kHz to 110 MHz Class 5
			Current probe Method: CISPR 25 (Edition 4) CISPR 25 (Edition 3)	150 kHz to 110 MHz Class 5
		Conducted Emission – Transients on power supply line (CTE)	ISO 7637-2 (Edition 3) ISO 7637-2 (Edition 2) AIS-004 (Part 3)	(±)12 V to (±)600 V Switching time $\Delta t_s = 300 \text{ ns} \pm 20\%$ with load $R = 0.6 \Omega$ $L = 50 \mu\text{H}$ @ 1 kHz
		Electrostatic Discharge Immunity (ESD) - Contact and Air Discharge	ISO 10605 (Edition 2) ISO 10605 Amd. 1	Level: (±) 200V to 30 kV $t_r = 0.7\text{ns to } 1\text{ns}$
RF Radiated Susceptibility –ALSE method	ISO 11452-2 (Edition 2) AIS-004 (Part 3)	80 MHz to 200 MHz, Level: 1V/m to 200V/m 200 MHz to 3200 MHz, Level: 1 V/m to 200 V/m		

Laboratory **SMIT EMI/EMC Laboratory, E-5/2, Chakan Industrial Area, Phase III, M.I.D.C., Nanekarwadi, Tal.- Khed, Pune, Maharashtra**

Accreditation Standard **ISO/IEC 17025: 2005**

Certificate Number **TC-8007**

Page 2 of 4

Validity **23.10.2018 to 22.10.2020**

Last Amended on --

Sl.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
		RF Radiated Susceptibility – Harness excitation methods Bulk current Injection method (BCI)	ISO 11452-4 (Edition 4) ISO 11452-4 (Edition 3) AIS-004 (Part 3)	1 MHz to 200 MHz Level: Up to 250mA 200 MHz to 400 MHz Level: Up to 200 mA
		Electrical disturbance conduction and coupling	Pulse 1 ISO 7637-2 (Edition 3) AIS-004 (Part 3)	(-) 20 V to (-) 600 V td = 2 ms & 1 ms tr = 0.5 µs to 1µs & 1.5 µs to 3 µs t1 ≥ 0.5 s t2 = 200ms t3 < 100 µs Supply voltage 60 V, 80 A
		Electrical disturbance conduction and coupling	Pulse 2 (a & b) ISO 7637-2 (Edition 3) AIS-004 (Part 3)	(+) 20V to (+) 150V, pulse 2a (+) 1V to (+) 60V, pulse 2b Pulse 2a td = 0.05 ms tr = 0.5 µs to 1 µs t1 = 0.2 s to 5 s Pulse 2b td = 0.2 s to 2 s t12 = 1 ms ± 0.5 ms tr = 1 ms ± 0.5 ms t6 = 1 ms ± 0.5 ms Supply voltage 60 V, 80 A

Laboratory SMIT EMI/EMC Laboratory, E-5/2, Chakan Industrial Area, Phase III,
M.I.D.C., Nanekarwadi, Tal.- Khed, Pune, Maharashtra

Accreditation Standard ISO/IEC 17025: 2005

Certificate Number TC-8007

Page 3 of 4

Validity 23.10.2018 to 22.10.2020

Last Amended on --

Sl.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
		Electrical disturbance conduction and coupling	Pulse 3(a & b) ISO 7637-2 (Edition 3) AIS-004 (Part 3)	(±) 25 V to (±)800 V Pulse 3a & Pulse 3b td = 150 ns ± 45 ns tr = 5 ns ± 1.5 ns t1 = 100 µs t4 = 10 ms t5 = 90 ms Supply voltage 60 V, 80 A
		Electrical disturbance conduction and coupling	Pulse 4 AIS-004 (Part 3)	Us: (-) 6 V to (-) 16V Ua: (-) 2.5V to (-) 12V tf : 9 ms to 11 ms t6 : 45 ms to 55 ms t7 : 45 ms to 55 ms t8 : 900 ms to 11,000 ms tr : 30 ms to 110 ms f : 2 Hz Supply voltage 60 V, 80 A
		Electrical disturbance conduction and coupling	Pulse 5(a & b) Load dump ISO 16750-2 (Edition 3) ISO 16750-2 (Edition 4)	(+)20 V to (+)200V, Pulse a & b: td : 40 ms to 400 ms tr : 5 ms to 10 ms Supply voltage 60V, 80A

Laboratory **SMIT EMI/EMC Laboratory, E-5/2, Chakan Industrial Area, Phase III, M.I.D.C., Nanekarwadi, Tal.- Khed, Pune, Maharashtra**

Accreditation Standard **ISO/IEC 17025: 2005**

Certificate Number **TC-8007**

Page 4 of 4

Validity **23.10.2018 to 22.10.2020**

Last Amended on --

Sl.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
		Electrical disturbance conduction and coupling	Capacitive coupling Fast pulses: ISO 7637-3 ISO 7637-3 (Edition 2)	(±) 25V to (±) 300V Pulse 3a & 3b: tr :3.5 ns to 6.5 ns td :0.105 µs to 0.195 µs t1 :100 µs t4 :10 ms t5 :90 ms Supply voltage 60V,80A
		Electrical disturbance conduction and coupling	Super imposed alternating voltage ISO 16750-2 (Edition 3) ISO 16750-2 (Edition 4)	10 Hz to 50 kHz, 1 Vpp to 10 Vpp t = 120s Supply voltage 60 V, 80 A
		Electrical disturbance conduction and coupling	ISO 16750-2 (Edition 3) ISO 16750-2 (Edition 4)	Timing info for: DC Supply Voltage:N.A Over Voltage: N.A Slow decrease & increase of supply voltage: (0.5 ± 0.1) V/min linear. Momentary drop in supply Voltage: tr & tf ≤ 10ms Reset behavior at voltage drop: t_hold : 5 s t_hold_Usmin : ≥ 10 s Supply voltage 4V to 60V,80 A